

Notice of References Cited

Application/Control No.

09/904,162

Applicant(s)/Patent Under
Reexamination
TSUDA ET AL.

Examiner

David S Blum

Art Unit

2813

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*		Document Number	Date	Name	Classification	
		Country Code-Number-Kind Code	MM-YYYY			
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	B	US-4999314 ✓	03-1991	Pribat et al	438	458
	C	US-				
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
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	V	NN960875 "Full Color Active Matrix Display Based on GaN Lateral Light Emitting Structures IMB Technical Disclosure 8/1996				
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.